# Study and application of X radiation sampling technique\*

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Abstract The physical bases of a X radiation sampling technique are investigated. Three technical problems of unevenness, matrix and heterogeneous mineralization effects, are considered and successfully resolved. This new technique was applied to three sites of Au, Sn and Cu deposits (representing higher, medial and lower atomic number minerals) in different exploration stages in China and satisfactory results are obtained.

Keywords X radiation sampling, Gold deposit, Copper deposit, Tin deposit

# 1 Introduction

Traditionally, determination of element concentrations in rocks, soil and stream sediments in exploration of mineral resources is based on sampling techniques. Analytical procedures usually include sampling; grinding the bulk sample into powder sample with less than 76 µm in diameter: analysing the element concentration of 3~5 g powder sample from ground sample. A common character of this traditional sampling is that the random relative errors produced in sampling, grinding and abstracting are usually far larger than in chemical and physical analyses. The turn-around time of determination of the elemental concentration of a sample is typically one week for mines or more. Energydisperse X-ray fluorescence (EDXRF) analysis offers several advantages over traditional samplings. One can directly measure in-situ with a portable X-ray fluorescent spectrometer. The turn-around time per spot of interest is only several minutes. The technique was defined as X radiation sampling.<sup>[1]</sup>

# 2 Theory

The physical basis of X radiation sampling is "Moseley law" i.e. the energy of the characteristic X-rays from the atom of an element is directly proportional to the square of the atomic number. So, when samples (e.g. powder, rock or soil) are irradiated with a radioactive isotope source, the types of elements can be quantitatively determined by measuring the energy

of the characteristic X-rays from the samples. Quantitatively determining the concentration of an aimed element in samples is based on the following formula<sup>[2]</sup>:

$$I_{\mathbf{x}} = \frac{KI_0}{\mu_0 + \mu_{\mathbf{x}}} \cdot F(H) \cdot C_{\mathbf{A}} \tag{1}$$

where  $I_{\mathbf{x}}$  is the intensity of the characteristic X-rays emitted from an aimed element;  $I_0$  the intensity of the (X or  $\gamma$ ) rays emitted from an isotope source;  $C_{\mathbf{A}}$  the concentration of the aimed element in samples;  $\mu_0$  and  $\mu_{\mathbf{x}}$  the mass attenuation coefficients of source (X or  $\gamma$ ) rays and characteristic X-rays, respectively; F(H) the unevenness factor relating to the unevenness of measured surface; K a constant. Main factors influencing Eq.(1) will be elucidated in the following.

#### 3 Method

### 3.1 Unevenness effect

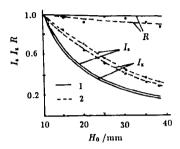
Unevenness effect in X radiation sampling is inevitable. According to the character of unevenness factor (F(H)), the following methods can be adopted to minimize unevenness effect: taking the ratio of characteristic X-rays to scattered radiation as a basic parameter, which can effectively reduce the errors caused by the changes of source-sample distance (see Fig.1); the formula of determining an optimal source-sample distance is:

$$\varepsilon_j = \frac{\sum_{i=1}^n (R(H_j + \triangle H_i) - R(H_j))}{n \cdot R(H_j)} \quad (2)$$

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where  $\varepsilon_j$  is the average of the absolute relative errors of the ratio of the elemental characteristic to scattered radiation; R the ratio of the elemental characteristic to scattered radiation ,  $H_j$  source-sample distance (10, 15, 20, 25, 30, 35, 40 mm) in model experiments, for any given  $H_j$  in model experiments,  $\triangle H_i$  can be -20, -15, -10, -5, 0, 5, 10, 15, 20 mm and 10 mm  $< H_j + \triangle H_i < 40$  mm; n the number of  $\triangle H_i$ . Ob-



 $\label{eq:Fig.1} \textbf{Fig.1} \ I_{\textbf{x}}, \ I_{\textbf{s}} \ \text{and} \ R \ \text{vs} \ H$   $I_{\textbf{s}} \text{--Scattered radiation intensity; 1----Theoretical;}$  2-----Experimental

## 3.2 Heterogeneous mineralization effect

Through a series of experiments, we found that the process of X radiation sampling can be described as normal distribution. Based on this theory, the best way to minimize the heterogeneous mineralization effect is to choose an optimal measuring net on sampling surface of interest, and the net should be as small as possible. The best net is  $d \cdot d$ , where d is the diameter of effective detection area of a probe in cm.

#### 3.3 Matrix effect

Under the condition of effectively overcoming unevenness effect, we established a model for overcoming matrix effect. That is

$$C_i = \varepsilon_i + \sum A_i R_i + \sum B_{i,j} R_i R_j + \sum C_{i,j,k} R_i R_j R_k$$

$$+\Sigma D_{i,j,k,h} R_i R_j R_k R_h + \cdots \tag{3}$$

where  $C_i$  is the concentration of the *i*-th element in the samples;  $R_i$  the ratio of the *i*-th element characteristic to the scattered radiation;  $R_j$ ,  $R_k$ ,  $R_h$  the ratios of the *j*-th, *k*-th, *h*-th element characteristic considered as main interfering elements in the samples to scattered radiation, respectively;  $\varepsilon_i$  the *i*-th element zero

viously, the minimum of  $\varepsilon_j$  gives the smallest relative error of the ratio of the characteristic to scattered radiation caused by the changes of source-sample distance.  $H_j$  producing the minimum of  $\varepsilon_j$  has been defined as the optimal source-sample distance( $H_0$ ). By experiment on simulating rock walls, the  $H_0$  values are determined as 23 mm for Sn (Fig.2), 16 mm for Pb-7n and 20 mm for Mo.

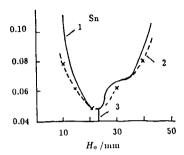


Fig.2 The experiment curve of the optimum source-sample distance for tin deposit

1—Theoretical; 2—Experimental; 3—Optimum source-sample distance

intercept;  $A_i$ ,  $B_{i,j}$ ,  $C_{i,j,k}$ ,  $D_{i,j,k,h}$  regressive coefficients.

To judge which elements are main interfering elements in samples, the following judgement expression is given

$$T_{j} = (\mu_{xj} - \mu_{sj}) \cdot \triangle C_{j} \tag{4}$$

where  $T_j$  is the judgement of the j-th elements;  $\triangle C_j$  the range of the j-th element concentration in samples;  $\mu_{\mathbf{x}j}$  and  $\mu_{\mathbf{s}j}$  the mass attenuation coefficient of the j-th element for characteristic X-rays and scattered rays of previous radiation, respectively.

# 4 Instrument

A microprocessor-based portable X-ray flourescence analyser was designed and manufactured at our university. It consists of a probe and a center unit, weighing 6 kg. The probe consists of a X-ray detector and an alternative isotope sources,  $^{238}$ Pu and  $^{241}$ Am; the  $^{238}$ Pu source is used to stimulate lower atomic number element K-shell and higher atomic number ele-

ment L-shell characteristic X-rays, and <sup>241</sup>Am

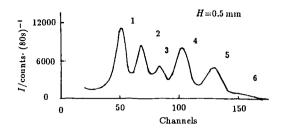


Fig.3 Experimental spectrum of Pb-Zn sample irradiated by <sup>238</sup>Pu source with a proportional probe

1. Fe $K_{\alpha}$ ; 2. Zn $K_{\alpha}$ ; 3. Pb $L_{\alpha}$ ; 4. Pb $L_{\beta}$ +scattered peak from U $L_{\beta}$ ; 5. Scattered peak from U $L_{\gamma}$ ; 6. Scattered peak from U $L_{\gamma}$ 

source is for stimulation of medial atomic number element K-shell characteristic X-rays and for measurement of scattered  $\gamma$  rays. Its dif-

ferential spectrum is shown in Fig.3. The centre unit includes a preamplifier, a linear pulse amplifier and analog-to-digital convertor that produces a 512 channel spectrum for storage in the microprocessor unit with automatic peak searching and curve smoothing function. Its output is a printer.

# 5 Applications

Since X radiation sampling technique is a non-destructive method of in-situ determining element concentration on the surface of original state rocks, ores, soil or stream sediment. It has been widely applied to mineral reconnaissance survey, mineral exploration and mining. We have successfully applied this technique to near thirty types of mineral deposits, such as Pb, Zn, Cu, Mo, Ba, Sn, Sb, Ag and Au, and obtained vast economical and social benefits.

# 5.1 Stage of reconnaissance survey

The working area is situated in the south of a large-scale gold deposit. No evidences

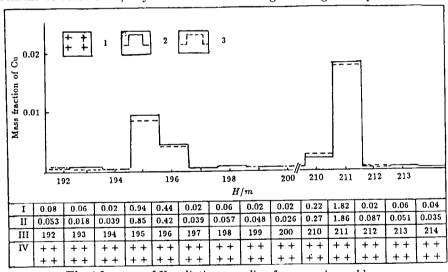


Fig.4 Isogram of X radiation sampling for surveying gold

1. Granite; 2. The curve of Cu grade determined by X radiation sampling; 3. The curve of Cu grade determined by channel-chemical sampling; I. Cu grade by X radiation sampling; II. Cu grade by channel-chemical sampling; III. The number of samples; IV. Lithology

showed that there was possibility of buried gold veins in this area before X radiation sampling technique was applied. According to strong correlation of As and gold, we determined the distribution of As in soil with X-ray fluorescence analyzer and successfully indicated gold veins (see Fig.4), which has been proved by drill holes

and tunnels later. This work gave a precious information about gold veins and took less than 20 d.

# 5.2 Stage of exploration

In this stage, we can easily use X radiation sampling to determine the border of ore bodies

and to estimate ore grades. Fig.5 is an example of applying the technique to determine Cu ore bodies and its grades in an exploratory trench. Two ore bodies were divided and exactly corresponded with those by traditional channel-chemical sampling methods

#### 5.3 Stage of mining

Table 1 is the statistical results of X ra-

diation sampling applied to Dachang tin mine in Guangxi province. In this mine, X radiation sampling technique has partly replaced traditional channel-chemical sampling method for determining tin ore grade and guiding mining. It is important that there is no pollution to environment and no harm to operators for X radiation sampling.

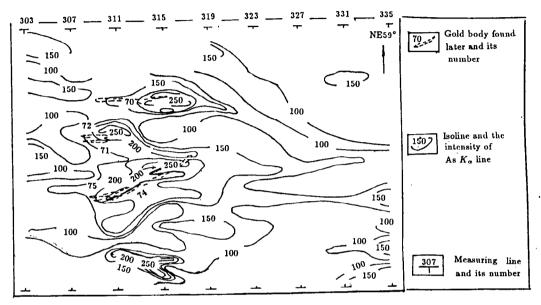


Fig.5 Composite profile of X radiation sampling on an exploration trench wall for determining Cu ore bodies

Table 1 Statistical results of X radiation sampling

Methods	Mass fraction	Number of	Relative	Cost of each	Turn-around
	of tin	samples	error	sample/RMB	time
X radiation sampling	$9.710 \times 10^{-3}$	105	$4.44 \times 10^{-3}$	0.7	1 h
Channel-chemical sampling	$9.068 \times 10^{-3}$	88	_	14	≥7 d

#### 6 Conclusion

X radiation sampling technique can be used to determine element concentration or ore grades on rock surface and in soil. So, it can be applied to outline mineralization anomaly in reconnaissance survey, to block out ore bodies in mineral exploration and to guide mining and estimate ore reserves in mining. Additionally, this technique is a non-destructive methods of directly measuring elements in ores under their

original state and can prevent the detriment of powdery stuff to health and lighten the labour intensity of workers.

#### References

- 1 Zhang Ye, Ge Liang-Quan. Nucl Geophys, 1994; 8(2):195
- 2 Ge Liang-Quan, Zhang Ye. Study on unevenness effect of radiation sampling and drilling fluid effect of X-ray fluorescence logging in nuclear geophysics .Ph D thesis. Beijing: China University of Geoscience, 1995

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